

**METHOD AND APPARATUS FOR TESTING A MEMORY DEVICE WITH
COMPRESSED DATA USING A SINGLE OUTPUT**

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ABSTRACT OF THE DISCLOSURE

A method and apparatus for testing a memory device with compressed data using multiple clock edges is disclosed. In one embodiment of the present invention data is written to cells in a memory device, the cells are read to generate read data, the read data is compressed to generate test data, and the test data is produced at a single output on edges of a clock signal.

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